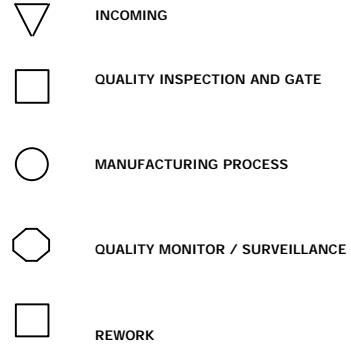


**ATTACHMENT 3.
TEST AND EOL FLOWCHART
INDUSTRIAL FLOW**

Vendor: Linear Technology Corporation
 Product: Bipolar or CMOS Process
 Package: All Package Types
 Location of Wafer Fab: Linear Technology Corp., Milpitas, CA./ Camas, WA.
 Assembly: Penang/Carsem/Unisem Malaysia Chinteik Thailand
 Final Test: Linear Technology Corp., Milpitas, CA., Singapore
 Q.C. Test: Linear Technology Corp., Milpitas, CA., Singapore
 Source Accept Test: Linear Technology Corp., Milpitas, CA., Singapore
 Quality Contact: Dwight Somerset, LTC, Milpitas, CA.
 (408) 432-1900 Ext. 2427



| FLOW CHART | PROCESS STEP | DESCRIPTION | INSPECTION/ TEST CRITERIA | METHOD & EQUIPMENT | SAMPLING PLAN | SPC TECHNIQUE |
|------------|--|--|---|---|--|--------------------------|
| | LTC INCOMING INSPECTION | CHECK QUALITY OF INCOMING ASSEMBLED MATERIAL | PACKAGE DIMENSION EXTERNAL VISUAL MARK PERMANENCY (IF INK MARK) SOLDERABILITY DIE ATTACH QUALITY LEAD FATIGUE TEST | OPTICAL COMPARATOR & CALIPERS 3X TO 30X MICROSCOPE MIL-STD-883 METHOD 2015 MIL-STD-883 METHOD 2003 DIE SHEAR LEAD FATIGUE TESTER | S/S = 2, ACC = 0 S/S = 76, ACC = 0 S/S = 4, ACC = 0 S/S = 3, ACC = 0 S/S = 5, ACC = 0 S/S = 10, ACC = 0 | % LAR TREND CHART |
| | CLASS TEST | ELECTRICAL TEST | TEST TO GUARDBANDED DATASHEET TEST LIMITS | INTEGRATED CIRCUIT TEST SYSTEM | 100% | MINIMUM YIELD CONTROL |
| | QA ELECTRICAL TEST @ +25°C | ELECTRICAL QUALITY | TEST TO GUARDBANDED DATASHEET TEST LIMITS | INTEGRATED CIRCUIT TEST SYSTEM | S/S = 315, ACC = 0 | PPM CHART |
| | QA ELECTRICAL TEST @ +85°C AND @ -40°C | ELECTRICAL QUALITY | TEST TO GUARDBANDED DATASHEET TEST LIMITS | LTX INTEGRATED CIRCUIT TEST SYSTEM | S/S = 125 ACC = 1 PARAMETRIC ACC = 0 FUNCTIONAL | PPM CHART |
| | EXTERNAL VISUAL INSPECTION | CHECK FOR PACKAGE QUALITY | VISUAL: BENT LEADS, LEAD FORM CRITERIA, MOLD VOIDS/CRACKS ETC | UNAIDED EYE | 100% | YIELD CHART |
| | QA POST PACK INSPECTION | PACKAGE/PACK QUALITY INSPECTION | VERIFY CORRECT TOP MARK, CORRECT PACK METHOD, CORRECT LABELLING, EXTERNAL VISUAL INSPECTION, BENT LEADS | 3X TO 10 X MICROSCOPE INSPECTION | S/S = 125, ACC = 0 | % LAR AND PPM P.A. CHART |
| | QA SHIPBENCH INSPECTION | PLANT CLEARANCE INSPECTION | PAPERWORK CHECK, VERIFY CORRECT PART NUMBER AND QUANTITY PAR COUNT | UN-AIDED EYE INSPECTION | LTPD = 2% S/S = 116, ACC = 0 | |
| | SHIP TO CUSTOMER | | | | | |